

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	±25	V
V _{GS}	Transient gate-source voltage (t _p ≤ 10 ns)	±35	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	13	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	8	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	52	Α
P _{TOT}	Total dissipation at T _C = 25 °C	25	W
dv/dt ⁽³⁾	Peak diode recovery voltage slope	15	V/ns
dv/dt ⁽⁴⁾	MOSFET dv/dt ruggedness	50	V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s, T_c = 25 °C)	2.5	kV
T _{stg}	Storage temperature range	-55 to 150	°C
Tj	Operating junction temperature range	-55 (0 150	C

- 1. Limited by maximum junction temperature
- 2. Pulse width limited by safe operating area.
- 3. $I_{SD} \le 13$ A, $di/dt \le 400$ A/ μ s, $V_{DS(peak)} < V_{(BR)DSS}$, $V_{DD} = 400$ V
- 4. $V_{DS} \le 480 \text{ V}$

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	5	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	62.5	°C/W

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AR}	Avalanche current, repetitive or not repetitive $(\text{pulse width limited by } T_{j\text{max}})$	2.7	А
E _{AS}	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	138	mJ

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2 Electrical characteristics

 T_C = 25 °C unless otherwise specified

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V _{GS} = 0 V, I _D = 1 mA	600			V
l	Zero gate voltage	V _{GS} = 0 V, V _{DS} = 600 V			1	μA
I _{DSS}	Drain current	V_{GS} = 0 V, V_{DS} = 600 V, T_{C} = 125 °C ⁽¹⁾			100	μΑ
I _{GSS}	Gate-body leakage current	V _{DS} = 0 V, V _{GS} = ±25 V			±10	μA
V _{GS(th)}	Gate threshold voltage	V _{DS} = V _{GS} , I _D = 250 μA	3.25	4	4.75	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 6.5 A		0.230	0.278	Ω

^{1.} Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	787	-	
C _{oss}	Output capacitance	V _{DS} = 100 V, f = 1 MHz, V _{GS} = 0 V	-	50	-	pF
C _{rss}	Reverse transfer capacitance		-	1.2	-	
Coss eq. (1)	Equivalent output capacitance	V _{DS} = 0 to 480 V, V _{GS} = 0 V	-	89	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	5.9	-	Ω
Qg	Total gate charge	V _{DD} = 480 V, I _D = 13 A, V _{GS} = 0 to 10 V (see Figure 15. Test circuit for gate charge behavior)	-	22	-	
Q _{gs}	Gate-source charge		-	3.5	-	nC
Q _{gd}	Gate-drain charge		-	10.5	-	

^{1.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching energy

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
F	Turn-off energy (from 90% V _{GS}	V_{DD} = 400 V, I_{D} = 2 A, R_{G} = 4.7 Ω , V_{GS} = 10 V	- 7.2	-	μJ	
E _{off}	to 0% I _D)	V_{DD} = 400 V, I_{D} = 5 A, R_{G} = 4.7 Ω , V_{GS} = 10 V	-	20.4	-	μJ

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Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V 000 V 1 0 5 4 5 4 7 0	-	10.5	-	ns
t _r	Rise time	V_{DD} = 300 V, I_{D} = 6.5 A, R_{G} = 4.7 Ω , V_{GS} = 10 V (see Figure 14. Test circuit for resistive load switching times and Figure 19. Switching time waveform)	-	5.2	-	ns
t _{d(off)}	Turn-off delay time		-	41	-	ns
t _f	Fall time		-	8	-	ns

Table 8. Source-drain diode

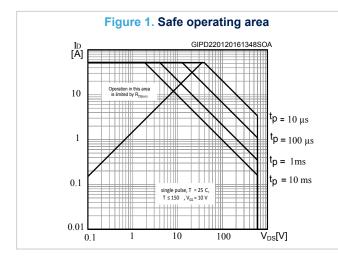
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		13	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		52	Α
V _{SD} (2)	Forward on voltage	V _{GS} = 0 V, I _{SD} = 13 A	-		1.6	V
t _{rr}	Reverse recovery time	I _{SD} = 13 A, di/dt = 100 A/μs, V _{DD} = 60 V (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	230		ns
Q _{rr}	Reverse recovery charge		-	2.3		μC
I _{RRM}	Reverse recovery current		-	20		Α
t _{rr}	Reverse recovery time	I_{SD} = 13 A, di/dt = 100 A/µs, V_{DD} = 60 V, T_j = 150 °C (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	287		ns
Q _{rr}	Reverse recovery charge		-	2.9		μC
I _{RRM}	Reverse recovery current		-	20.2		Α

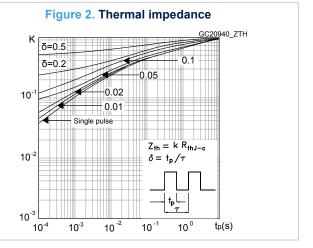
- 1. Pulse width is limited by safe operating area
- 2. Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

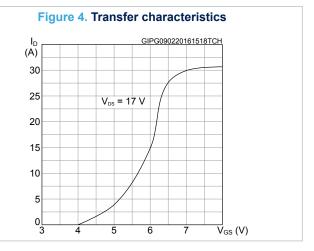
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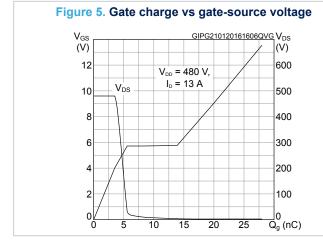


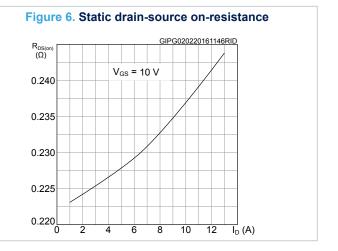
2.1 Electrical characteristics (curves)











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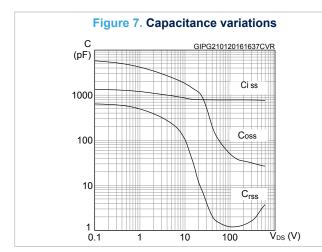


Figure 8. Output capacitance stored energy

Eoss (µJ)
6
5
4
3
2
1
0
100 200 300 400 500 600 V_{DS} (V)

Figure 9. Normalized V_{(BR)DSS} vs temperature

V_{(BR)DSS} (norm.)

1.08

1.04

1.00

0.96

0.92

0.88

-75

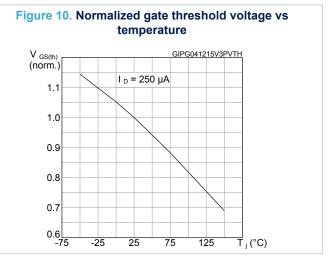
-25

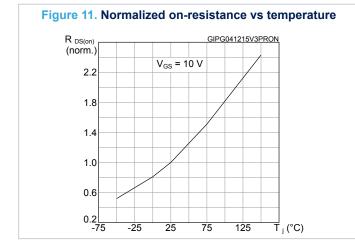
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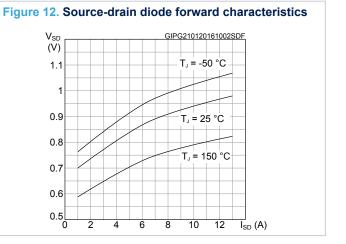
75

125

T_j (°C)

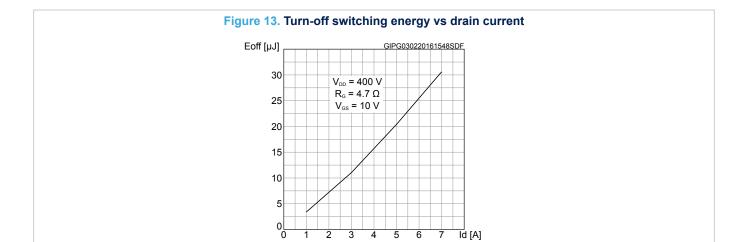






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3 Test circuits

Figure 14. Test circuit for resistive load switching times

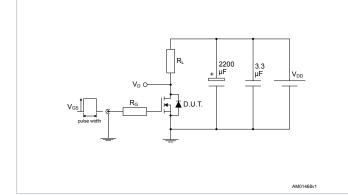


Figure 15. Test circuit for gate charge behavior

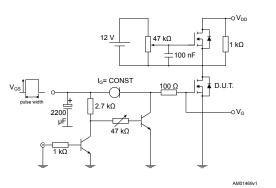


Figure 16. Test circuit for inductive load switching and diode recovery times

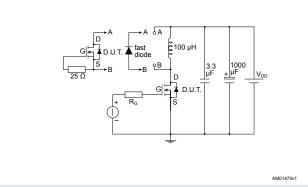


Figure 17. Unclamped inductive load test circuit

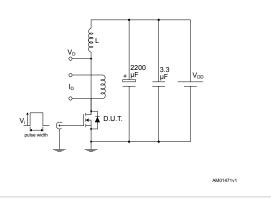


Figure 18. Unclamped inductive waveform

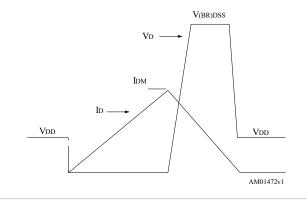
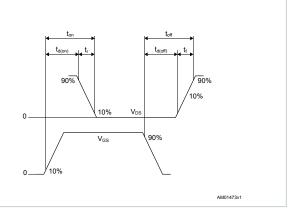


Figure 19. Switching time waveform



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4 Package information

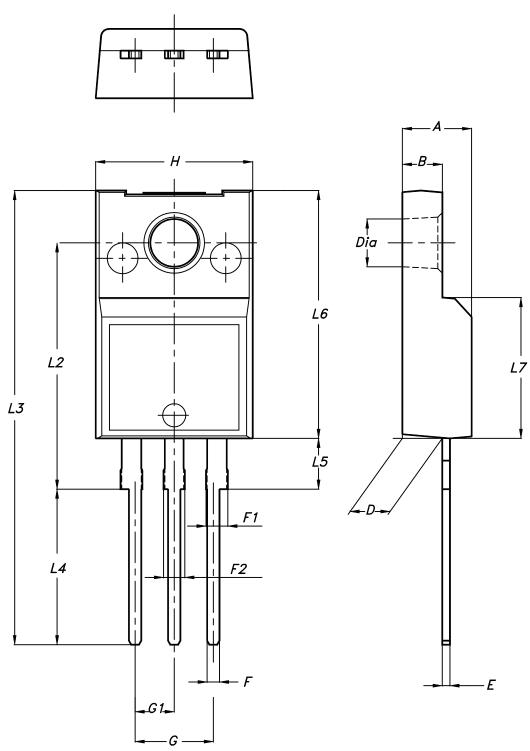
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

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4.1 TO-220FP package information

Figure 20. TO-220FP package outline



7012510_Rev_12_B



Table 9. TO-220FP package mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
Α	4.4		4.6
В	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2



Revision history

Table 10. Document revision history

Date	Revision	Changes
29-Feb-2016	1	First release.
18-Aug-2016	2	Modified: Table 2: "Absolute maximum ratings"
		Minor text changes
		Removed maturity status indication from cover page. The document status is production data.
02-Mar-2018	3	Updated Table 1. Absolute maximum ratings, Table 4. On/off states and Table 5. Dynamic.
		Updated Figure 1. Safe operating area, Figure 3. Output characteristics, Figure 4. Transfer characteristics and Figure 5. Gate charge vs gate-source voltage.
		Minor text changes.
		Modified Table 1. Absolute maximum ratings.
04-Jun-2018	4	Modified Figure 1. Safe operating area .
04-Juli-2016	4	Modified Table 8. Source-drain diode.
		Minor text changes.







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